

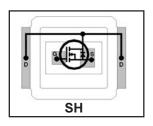
## DIGITAL AUDIO MOSFET

# IRF6665PbF IRF6665TRPbF

#### **Features**

- Latest MOSFET Silicon technology
- Key parameters optimized for Class-D audio amplifier applications
- Low R<sub>DS(on)</sub> for improved efficiency
- Low Q<sub>g</sub> for better THD and improved efficiency
- Low Q<sub>rr</sub> for better THD and lower EMI
- Low package stray inductance for reduced ringing and lower EMI
- Can deliver up to 100W per channel into  $8\Omega$  with no heatsink ®
- Dual sided cooling compatible
- Compatible with existing surface mount technologies
- RoHS compliant containing no lead or bromide
- •Lead-Free (Qualified up to 260°C Reflow)

Key Parameters							
$V_{DS}$	100	٧					
$R_{DS(on)}$ typ. @ $V_{GS} = 10V$	53	mΩ					
Q <sub>g</sub> typ.	8.7	nC					
R <sub>G(int)</sub> typ.	1.9	Ω					





Applicable DirectFET Outline and	Substrate Outline	(see p. 6, 7 for deta	ils)
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SQ SX ST SH MQ MX	MT	MN		
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## **Description**

This Digital Audio MOSFET is specifically designed for Class-D audio amplifier applications. This MOSFET utilizes the latest processing techniques to achieve low on-resistance per silicon area. Furthermore, gate charge, body-diode reverse recovery and internal gate resistance are optimized to improve key Class-D audio amplifier performance factors such as efficiency, THD, and EMI.

The IRF6665PbF device utilizes DirectFET™ packaging technology. DirectFET™ packaging technology offers lower parasitic inductance and resistance when compared to conventional wirebonded SOIC packaging. Lower inductance improves EMI performance by reducing the voltage ringing that accompanies fast current transients. The DirectFET™ package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques, when application note AN-1035 is followed regarding the manufacturing method and processes. The DirectFET™ package also allows dual sided cooling to maximize thermal transfer in power systems, improving thermal resistance and power dissipation. These features combine to make this MOSFET a highly efficient, robust and reliable device for Class-D audio amplifier applications.

#### **Absolute Maximum Ratings**

	Parameter	Max.	Units
V <sub>DS</sub>	Drain-to-Source Voltage	100	V
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	
<sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	19	
<sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	4.2	A
<sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	3.4	
DM	Pulsed Drain Current ①	34	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	42	W
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation ③	2.2	
P <sub>D</sub> @T <sub>A</sub> = 70°C	Power Dissipation ③	1.4	
	Linear Derating Factor	0.017	W/°C
Γ <sub>J</sub>	Operating Junction and	-40 to + 150	°C
T <sub>STG</sub>	Storage Temperature Range		

#### Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient 39		58	°C/W
$R_{\theta JA}$	Junction-to-Ambient © ®	12.5		
$R_{\theta JA}$	Junction-to-Ambient ⑦⑨	20		
$R_{\theta JC}$	Junction-to-Case ® 9		3.0	
Ralper	Junction-to-PCB Mounted	1 4		

Notes ① through @ are on page 2

## Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.12		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		53	62	mΩ	$V_{GS} = 10V, I_D = 5.0A \oplus$
$V_{GS(th)}$	Gate Threshold Voltage	3.0		5.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 100V, V_{GS} = 0V$
				250		$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100		$V_{GS} = -20V$
R <sub>G(int)</sub>	Internal Gate Resistance		1.9	2.9	Ω	

## Dynamic @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	6.6			S	$V_{DS} = 10V, I_D = 5.0A$
$Q_g$	Total Gate Charge		8.4	13		$V_{DS} = 50V$
$Q_{gs1}$	Pre-Vth Gate-to-Source Charge		2.2			$V_{GS} = 10V$
Q <sub>gs2</sub>	Post-Vth Gate-to-Source Charge		0.64			$I_D = 5.0A$
$Q_{gd}$	Gate-to-Drain Charge		2.8		nC	See Fig. 6 and 17
$Q_godr$	Gate Charge Overdrive		2.8		1	
$Q_{sw}$	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )		3.4		1	
t <sub>d(on)</sub>	Turn-On Delay Time		7.4			$V_{DD} = 50V$
t <sub>r</sub>	Rise Time		2.8		1	$I_{D} = 5.0A$
t <sub>d(off)</sub>	Turn-Off Delay Time		14		ns	$R_G = 6.0\Omega$
t <sub>f</sub>	Fall Time		4.3		1	V <sub>GS</sub> = 10V ④
C <sub>iss</sub>	Input Capacitance		530			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		110		1	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		29		рF	f = 1.0MHz
C <sub>oss</sub>	Output Capacitance		510			$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
C <sub>oss</sub>	Output Capacitance		67			$V_{GS} = 0V, V_{DS} = 80V, f = 1.0MHz$
C <sub>oss</sub> eff.	Effective Output Capacitance		130		1	$V_{GS} = 0V$ , $V_{DS} = 0V$ to 80V $\odot$

## **Avalanche Characteristics**

	Parameter	Тур.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy®		11	mJ
I <sub>AR</sub>	Avalanche Current ①		5.0	Α

## **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current			38		MOSFET symbol
	(Body Diode)				Α	showing the
I <sub>SM</sub>	Pulsed Source Current			34		integral reverse
	(Body Diode) ①					p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25$ °C, $I_S = 5.0$ A, $V_{GS} = 0$ V ④
t <sub>rr</sub>	Reverse Recovery Time		31		ns	$T_J = 25^{\circ}C$ , $I_F = 5.0A$ , $V_{DD} = 25V$
Q <sub>rr</sub>	Reverse Recovery Charge		37		nC	di/dt = 100A/μs

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- @ Starting  $T_J$  = 25°C, L = 0.89mH,  $R_G$  = 25  $\!\Omega,\,I_{AS}$  = 5.0A.
- 3 Surface mounted on 1 in. square Cu board.
- 4 Pulse width  $\leq 400 \mu s$ ; duty cycle  $\leq 2\%$ .
- © Used double sided cooling , mounting pad.
- Mounted on minimum footprint full size board with metalized back and with small clip heatsink.
- $\ \, 9 \ \, R_{\theta}$  is measured at  $T_{J}$  of approximately 90°C.
- 9 Based on testing done using a typical device & evaluation board at Vbus=±45V,  $f_{SW}$ =400KHz, and  $T_{A}$ =25°C. The delta case temperature  $\Delta T_{C}$  is 55°C.

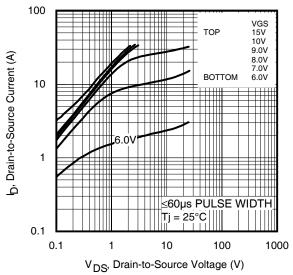


Fig 1. Typical Output Characteristics

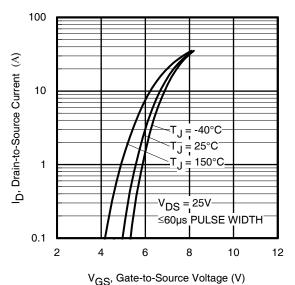
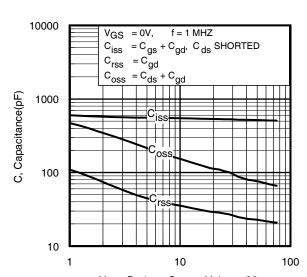


Fig 3. Typical Transfer Characteristics



V<sub>DS</sub>, Drain-to-Source Voltage (V) **Fig 5.** Typical Capacitance vs.Drain-to-Source Voltage www.irf.com

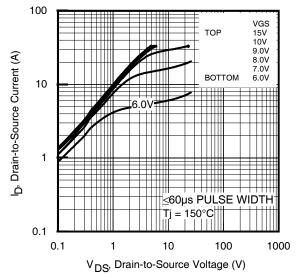


Fig 2. Typical Output Characteristics

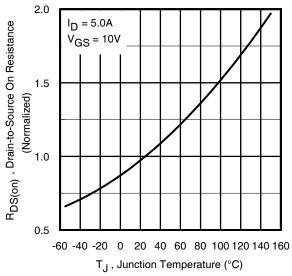


Fig 4. Normalized On-Resistance vs. Temperature

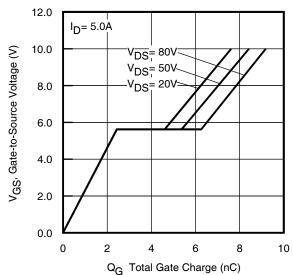


Fig 6. Typical Gate Charge vs.Gate-to-Source Voltage

## IRF6665PbF

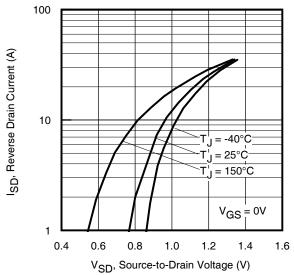


Fig 7. Typical Source-Drain Diode Forward Voltage

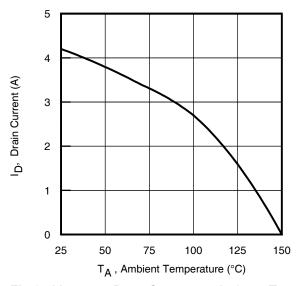
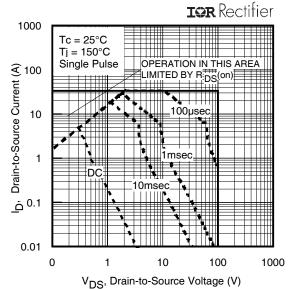


Fig 9. Maximum Drain Current vs. Ambient Temperature



International

Fig 8. Maximum Safe Operating Area

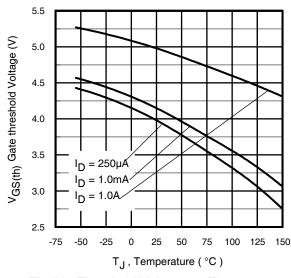


Fig 10. Threshold Voltage vs. Temperature

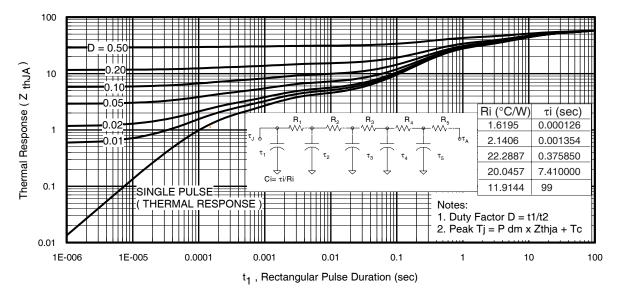
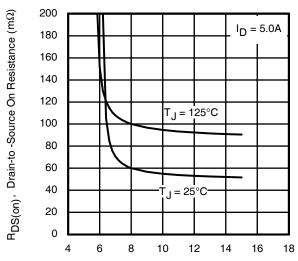


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient 3

## IOR Rectifier



V<sub>GS,</sub> Gate -to -Source Voltage (V)

Fig 12. On-Resistance vs. Gate Voltage

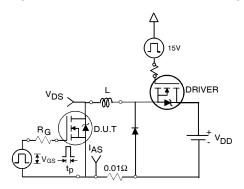


Fig 15a. Unclamped Inductive Test Circuit

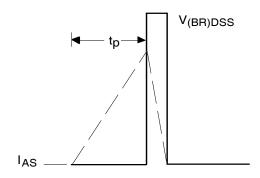
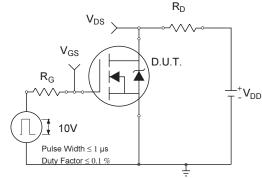


Fig 15b. Unclamped Inductive Waveforms



**Fig 16a.** Switching Time Test Circuit www.irf.com

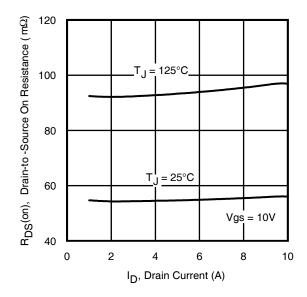


Fig 13. On-Resistance vs. Drain Current

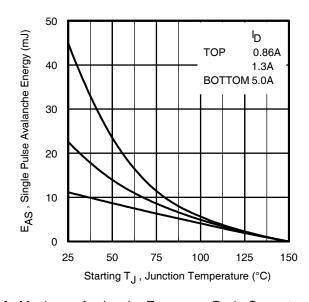


Fig 14. Maximum Avalanche Energy vs. Drain Current

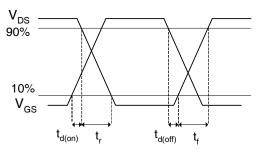
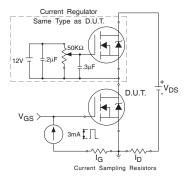


Fig 16b. Switching Time Waveforms



Vgs(th)

Qgs1 Qgs2 Qgd Qgodr

Fig 17a. Gate Charge Test Circuit

Fig 17b. Gate Charge Waveform

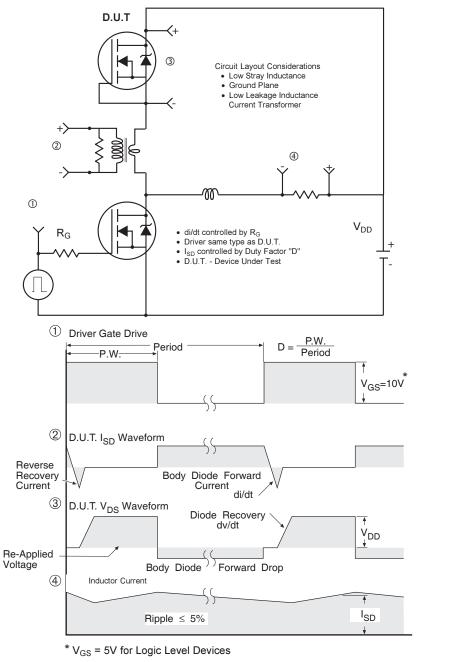
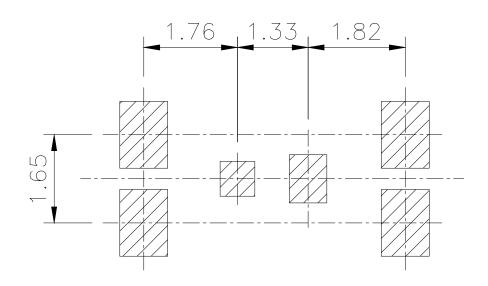
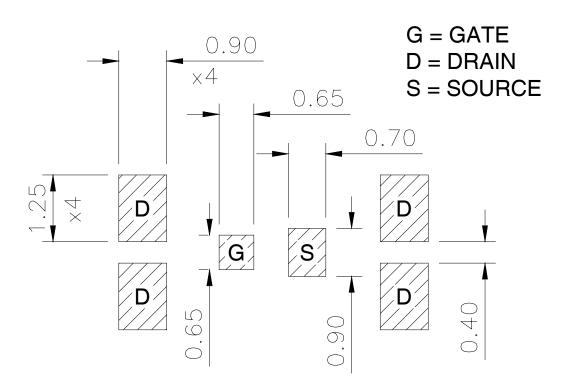


Fig 18. Diode Reverse Recovery Test Circuit for N-Channel HEXFET® Power MOSFETs

# DirectFET™ Substrate and PCB Layout, SH Outline (Small Size Can, H-Designation).

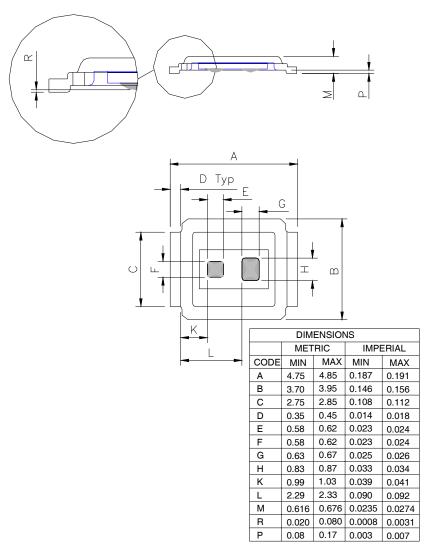
Please see DirectFET application note AN-1035 for all details regarding PCB assembly using DirectFET. This includes all recommendations for stencil and substrate designs.



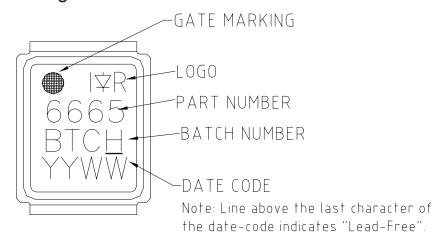


# DirectFET™ Outline Dimension, SH Outline (Small Size Can, H-Designation).

Please see DirectFET application note AN-1035 for all details regarding PCB assembly using DirectFET. This includes all recommendations for stencil and substrate designs.

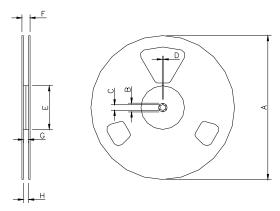


## DirectFET™ Part Marking



## IRF6665PbF

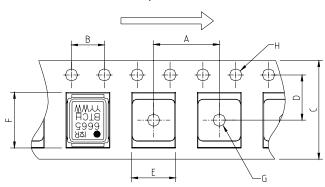
## DirectFET™ Tape & Reel Dimension (Showing component orientation).



NOTE: Controlling dimensions in mm Std reel quantity is 4800 parts. (ordered as IRF6665TRPBF). For 1000 parts on 7" reel, order IRF6665TR1PBF

	REEL DIMENSIONS								
S	STANDARD OPTION (QTY 4800)					1 OPTION	(QTY 10	00)	
	ME	TRIC	IMP	ERIAL	ME	TRIC	IMP	ERIAL	
CODE	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
Α	330.0	N.C	12.992	N.C	177.77	N.C	6.9	N.C	
В	20.2	N.C	0.795	N.C	19.06	N.C	0.75	N.C	
С	12.8	13.2	0.504	0.520	13.5	12.8	0.53	0.50	
D	1.5	N.C	0.059	N.C	1.5	N.C	0.059	N.C	
Е	100.0	N.C	3.937	N.C	58.72	N.C	2.31	N.C	
F	N.C	18.4	N.C	0.724	N.C	13.50	N.C	0.53	
G	12.4	14.4	0.488	0.567	11.9	12.01	0.47	N.C	
Н	11.9	15.4	0.469	0.606	11.9	12.01	0.47	N.C	

### Loaded Tape Feed Direction



DIMENSIONS							
	ME	TRIC	IMPERIAL				
CODE	MIN	MAX	MIN	MAX			
Α	7.90	8.10	0.311	0.319			
В	3.90	4.10	0.154	0.161			
C	11.90	12.30	0.469	0.484			
D	5.45	5.55	0.215	0.219			
Е	4.00	4.20	0.158	0.165			
F	5.00	5.20	0.197	0.205			
G	1.50	N.C	0.059	N.C			
I	1.50	1.60	0.059	0.063			

Data and specifications subject to change without notice. This product has been designed and qualified for the Consumer market. Qualification Standards can be found on IR's Web site.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903 Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

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